

Cross-Layer Reliability



Error management at different design layers: **technology, hardware, software.**

Reliability engineers and system architects are required to fulfill demanding safety requirements to budget and to allocate reliability targets per system component while depending on incomplete or missing reliability data



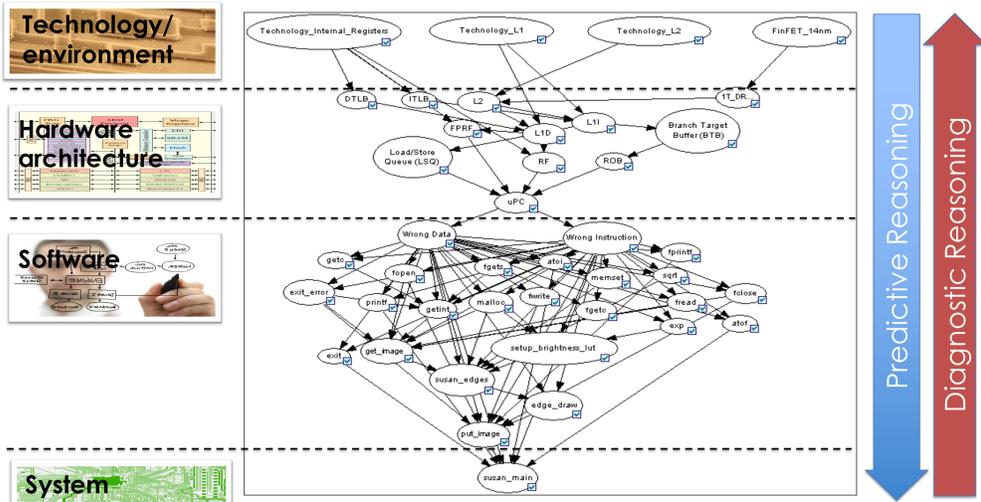
A safe approach: OVERDESIGN
Large margins
Massive redundancy

Reliability Costs



Can tools to evaluate reliability early in the design help designing more efficient systems?

System Reliability Analyzer



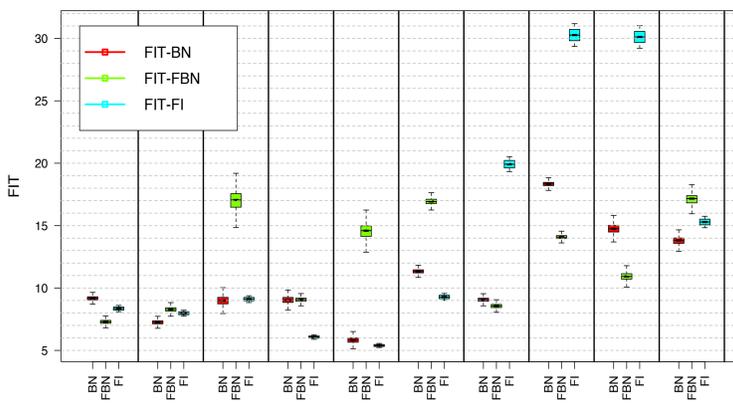
Component-Based Bayesian Network (BN) reliability model

- Nodes represent HW/SW system's components.
- Edges represent error masking/propagation paths within the system
- Masking probability computed through our library of dedicated tools

Reasoning:

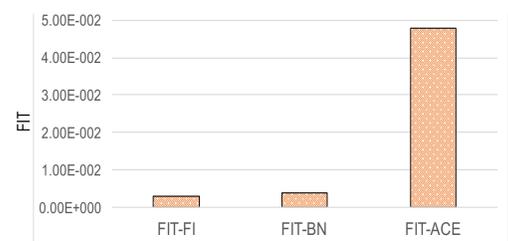
- **Diagnostic** from symptoms (i.e., system failures) we update our belief about causes of failures.
- **Predictive** from causes (i.e., raw technology failure rates) we obtain new beliefs about their effects (i.e., system failures).

Some results:

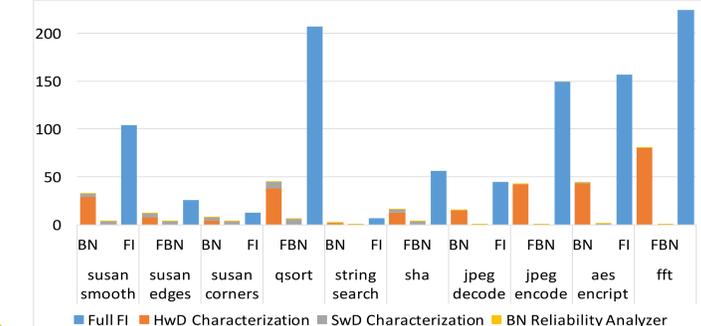


Technology: 22nm Bulk Planar
Hardware architecture: x86 out-of-order CPU Register file (256 regs each 64-bits) 32KB L1 Instruction Cache 32KB L2 Data Cache 1MB L2 Cache 128 B Load/Store Queue 4GB ECC Protected DRAM

FIT estimation for a x86 based system running 10 software benchmarks: (1) FIT_{BN} computed with the CLERECO model, (2) FIT_{FBN} computed with the CLERECO model using average masking probabilities, (3) FIT_{FI} computed using full fault injection campaigns



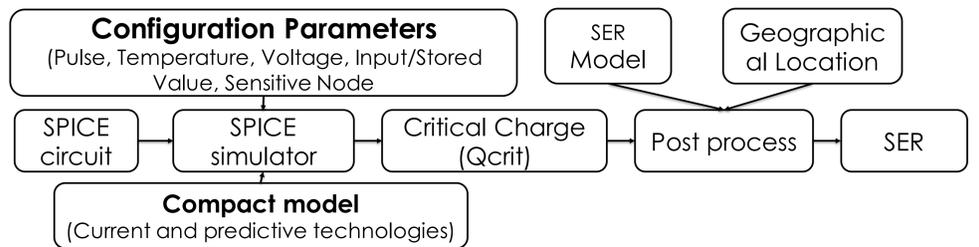
Comparison with AVF computed through ACE analysis for the string search benchmark computed with technology: FIT_{BN} computed with the CLERECO model, FIT_{FI} computed using full fault injection campaigns, FIT_{ACE} computed using ACE analysis with literature data



Simulation time comparison in hours of simulation: BN: CLERECO Bayesian Reliability Analyzer FI: full micro architectural level fault injection campaign.

Technology/Environment Analyzer

Soft-errors characterization tool suite for different technologies and basic building blocks



CLERECO Tech. Library

Technology (CMOS)	Technology node
Bulk Planar (ASU PTM Models)	22nm and 16nm
Bulk FinFET (ASU PTM Models)	20nm and 14nm
SOI Planar (UTSOI Model)	22nm

Circuits

SRAM Cells 6T/8T/10T
Flip Flop - D
Latch
Logic Gates

Hardware Vulnerability Analysis

Tool suite to characterize hardware vulnerability to faults for different categories of components

- Transient, intermittent and permanent faults, targeting one or multi bits at one or more components.
- Analysis based on:
 - Analytical models
 - Statistical fault injection based on architectural models

CPUs

x86-64 OoO model (general x86, x86-64 ISA support)
ARM OoO A9/A15 models (general ARM ISA support)

GPUs

NVIDIA G80, GT200 and Fermi, AMD Southern Island, Evergreen

Memories

SRAM, DRAM, SSD (NAND Flash, STT MRAM)

Custom cores and peripherals

Interconnections
AMBA, PCI Express, NoCs

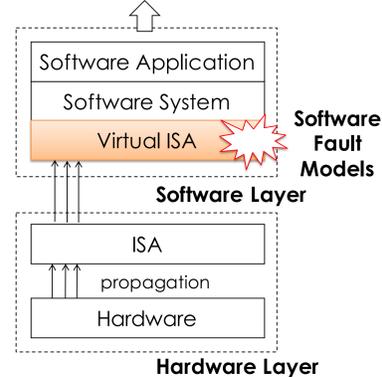
Software Vulnerability Analyzer

Virtual ISA-based Fault Injection

- **Virtual ISA:** LLVM (A framework that uses virtualization to perform complex analysis of software applications on different architectures)
- **Fault models:** Software Fault Model (Effect of soft errors on the virtual ISA)

Fault Model	Description
Wrong Data in an Operand	An operand of the VISA instruction changes its value
Not accessible Operand	An Operand of the VISA instruction cannot change its value
Instruction Replacement	An instruction is used in place of another
Control Flow Error	The Control Flow is not respected

Software Faulty Behaviors



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